Farm PTO-1449					T OF COMMERCE DEMARK OFFICE	ATTY, DOCKET N				
	•	LIST OF ART CITED				: al	*			
				FILING DATE				GRC 2818		
				U.S. PATE	NT DOCUMENTS					
*Ezaminar Imital	-	Document Number	Date		Neme	<u>-</u>	Qui	Subclass	Filing If Appro	Date prists
PO	AA	5,171,379	12/1997	Kumar st	al.					
	AΒ	4,923,531	05/1990	Flaher						
	AC.	5,189,503	9/1993	Suguro						
P.D	ΑĐ	6,348,139	09/1993	Inoue			/	1		
	AE									
	af					,				
	AG			<u> </u>						
	AH									
	IA.									
	AJ					:				
	AK			<u> </u>		· <u>-</u>				
-	AL			<u> </u>					• •	
				POREIGN PA	TENT DOCUMEN	TS ·		<u> </u>	· ·	
		Document Number	Date		Country		Class	Subclass	Trans. Yes	lation No
PD	АМ	252.442	09,06,1960	Australia			į			
PD	AN	55-179784	12/1980	Japan						
	AO			ļ						
	AF								-	
	40			}		<u>,</u>		L	<u> </u>	
	,					, Parlicant Pages, Etc.				
PD	AR.	Hughes et al., "Gr Malorials Society,	uin Subdivision 1996, pgs. 257-2	and the Deve 252. (Year is a	lopment of Local Countries of Lo	Plantations in Railed that the month is not	Tantolum" 7 an issue.)	Contolum, Ti	o Minerals, M	atals &
					A SECOND					
PD	AS	Arit. Jr., "Sulfonal pp. 541-564, (1993)	ion and Sulfons Year is sulficie	ation to Thorif	im and Thorium Co	prepounds" Klyk-Orbini not an issue).	r Encyclope	dla of chem	ical Technolog	y vol. 22,
						· · · · · · · · · · · ·	******			
PD	AT	Kirkbride at al 393-403, 1965. (Ya	The Effect of Yi er is sufficiently	irium on the	Recrystallization as the month is not a	nd Orain Orosch of Tan Issue.)	mtajko. 1.	Less-Comm	Matala vol.	9, pp.
			· ·							
examiner	<u> </u>	PHUC T. DA	NG	T	DATE CONSIDER	T(3/2	2003			
*EXAMINER	Initial I	f reference considered, when	her or got elteric	on is in confe	rmance with MPE				formance and	not
		py of this form with past cor		ърричеви.						

Form PTO-14	19		ATTY. DOCKET NO. SERIAL NO. 10/053,201							
		LIST OF ART CITED		APPLICANT Henry Rosenberg et al						
				FIUNG DATE GROUP JENUTY 15. 2002 2213						
			, _	U.S. PATENT DOCUMENTS	1					
*Examiner Initial		Document Number	Date	Name		Class	Subclass Fling Dete			
	AA									
	AB			·						
	AC									
	4			·						
	AE									
	AF									
	AÛ									
	AH									
	7					*				
	Z									
	AK								••	
,	AL	·							-	
				FOREIGN PATENT DOCUMEN	צון			•	1	
'		Document Number	Date	Сошьсту		Class	Subclass	Yes	istios No	
	AM									
	AN		ļ				•			
	AO						,			
	AP.		 		.atzesti si					
	AQ		<u> </u>		THE PARTY OF THE P	lL		<u></u>		
			*	CES (including Author, Title, Def	i, Perilocat Pages, Etc.;					
Po	AR	National Research	Corporation Pres	s Release, pgs. 1-4, July 1964,						
PD	ΑŜ	National Research	Corporation Date	Sheet "SGS Talahum", pgs. 1-7,	no date.					
				-	•		,,			
PP	AT	ASTM Standard Synthesis than the month is	ASTM Standard Specification for Tantalum and Tantalum Alloy Plata, Sheet, and Strip, pgs. 558-56), 1992. (Year a sufficiently early so that the month is not an insue.)							
			,						·	
EXAMINER		PHUC T.	DANG	DATE CONSIDER	RED 7/3/	2003	•			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 60%. Draw line through distinuit if not in conformance and dat considered. Include copy of this form with next communication to applicant.										

Form PTO-16	149		U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. SERIAL NO. PATENT AND TRADEMARK OFFICE 34593-CON1 10/053,201						
		LIST OF ART CITED		NT	APPLICANT Harry Rosenberg	ot al			·
				FILING DATE Jaquery 15, 2002			GROUP 2818		
				U.S. PATENT DOCUMENTS					
*Exeminer Initlal		Dogument Number	Dete	Nama		Class Subcla		asa Filing Date If Appropriate	
	` 🗚								·
	AB.								-
	AC								
	A.D						<u></u>		
	AP					1			
	AP								
	AG				····				
	AH								
	AI				·				
	م			·					
	98/								
	AL				_	·			
	1			FOREIGN PATENT DOCUMEN	TTS .			1	
		Document Number	Dale	Country		Class	Subclass		dation
	AM			A STATE OF THE STA		1		Yes	No
	AN			<i>p</i>					
	AO		1						
	ΑÞ				- <u>-</u>				
	10		1/						
		οπ	er referen	CES (including Author, Title, Date	a, Partianat Pagas, Etc.	.)			
PD	AR	Kumer, et al, "Ell vol. 322, pgs. 413-	ect of Intermete 122, 1994. (Year	lic Compounds of the Propertie is sufficiently early so that the	s of Tantalum" Mater mouth is not as laste	rial» Rassarci)	Society Syd	appalum Proc	nedings,
				····					
PD	24	Kumur. et al. "Eff 40, 1994. (Year is	ect of Intermeta sufficiently early	illic Compounds of the Propertie y so that the month is get as is	s of Tanialum*Refrac	tory Metals (R Hard Mate	rials, vol. 12	рда. 35-
						· · · · · · · · · · · · · · · · · · ·		··	
PD	AT	Kleic at al., "Inho early so that the u	Kloie at al., "Inhomogeneous Textures in Tentalum Sheets" Materials Science Forum, vol. 157-162, pgs. 142 early so that the month is not an inves.)						milicie atly
					37				
EXAMINER	<u> </u>	HUC T. DA	NG.	DATE CONSIDER	7/3/	2003	3		
*EXAMINER	l: loitial i Include cop	f reference considered, whether	her or not dieth Manunication to	on is la roaformance with MPEI applicant.	609: Draw line thro	ugh citation i	il sot in tobi	ormance and	got

JOHN PS



5098383424 P.26 Page 4 of 5

	•		34593-CON1 10/053,201						
		LIST OF ART CITED (Use several sheets		TA	APPLICANT Harry Rossabera	at al			
					FILING DATE Jenuary 15, 2002		GRO 2818	UP	
				U.S. PATENT DOCUMENTS					
*Eraminer Initial		Document Number	Date	Name	,	Class	Subclass	Pling: If Appro	Date opriate
	AA					·		*	
	AB								
	AC								·
	. AD								
	AB.					1_			
	AP	*		<u> </u>				<u> </u>	
	AG		<u> </u>		<u>-</u>			ــــــ	
	AH	(4)						 	
	AJ							├──	
	AJ		ļ	<u> </u>					
	AL		<u> </u>					 	
			<u> </u>	TOTAL DESIGNATION OF THE PARTITION OF TH	_				•
		Document	Date	FOREIGN PATENT DOCUMENT	13	Class	Subclus	Тгали	dation
		Number	,	<u> </u>		 		Y•3	No
	AM		 						
	AQ				E Comment				
	AP	·		- Committee		<u> </u>			
~	AQ			Bereit					
		от:	HER REFERENC	CES (igcludide Author, Title. Date	. Pertinent Pages. Etc	E.)			
PA	AR	Clark et al. "influ Transactions, vol. 2		restabling on the Microstructure	il and Texture Deve	lopment in Po	us Tantalum'	', Metallurgio	al
				•					
PP	AS	Roabe, at al., "Tax April 1994,	aura and Misros	structure of Rolled and Annealed	Tantalum", Materia	als Science and	d Technology	, Vol. 10. pg:	. 299-305,
PD	AT	Wright ot al., "Tex	dws Gradient E	Mecte in Testalum". Internations	d Conference on Ter	atures of Mate	eciala 7 pga.	September 15	993.
EXAMINER		PHVC T.	DANG	DATE CONSIDER	ED 7/3	1200	3		
"EXAMINER:	Initial (I	f reference considered, wheth y of this form with next son	ser or not clistic namualcation to s	on is in conformance with MPEP applicant.	609; Draw line thro	inte citation p	oot in conf	ormance and	not ,

Form PTO-1449				PARTMENT OF COMMERCE 'AND TRADEMARK OFFICE	ATTY. DOCKETNO. SIRIA! NO. 14593-CON1 10/053-201					
		LIST OF ART CITED	APPLICANT Harry Rosenborg or si							
	•	•		•				GROUP 2816		
				U.S. PATENT DOCUMENTS						
'Emminer Initel		Ducum cor Number	Data	Namo		Class	31924	Filing Date If Appropriate		
	AA									
	AB									
	AC			, ·						
	AD									
	Æ									
	AF									
	AG						_			
	AH				:			<u> </u>		
	A									
	لد ا									
				FOREIGN PATENT DOCUMEN	18			·····		
		Document Number	Date	Cougliy		Cjón	Subclass	Trans	lation No	
	AK			A SECTION ASSESSMENT						
	AL			(Japan)						
	АМ			Side of the same o					<u> </u>	
	AN		3	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,				1		
	AO									
	· · · · · · · · · · · · · · · · · · ·	0	THER REFERE	CES (inducing Author, Title, Dat	e, Pertinent Pages. Stc.)		_			
PD	AP	Wright at al., Textu pgs. 1-17. (Year is ma	ral and Microstruc (Ecleptly early so (rural Gradiem Effects on the Macha hat the mouth is not an lawe.)	nical Bahavior of a Tanta	lum Plate". Met	al)wylcal Tr	nometions A, 25	iA(1994).	
				•						
PD	ΑQ	Clark et al. "Ellact : 2039-2047).	Clark et al. "Effect of Processing Variables on Texture and Texture Gradients in Tantalum", Mutallurgical Transactions A, Vol. ZZA. September 1991, pgs. 2009-2047).							
								•		
PD AR Kumar et al. "Corrogion Registant Proporties of Tantalum"					hpar No. 253, 14 pages. (8	No date)				
				<u>.</u>						
EXAMINER	PHUC T. PANG DATE CONSIDERED 7/3/2003									
EXAMINER:	u up me	farence considered, whether out communication to applicant	or not citation is in L	conformance with MPEP 609; D	raw line through citation	if not in confo	mande and	not considere	d, Include	